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INFORMATION DISCLOSURE STATEMENT

Applicant: Franz Hofmann et al.

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27 November 2003~~Group Art. Unknown~~

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Examiner Initial	Document No.	Date	Name	Class	Sub Class	Filing Date If Appropriate
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03/028124	04/2003	WO			Yes (Abstract Only)
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OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

	Copy of International Search Report having PCT Application No. PCT/DE03/03935 mailed on July 22, 2004.
	Kohlrausch, F., "Practical Physics, vol. 2, 23rd Edition, Teubner Verlag Stuttgart, 1985, pages 31-32, <concise explanation included.>
	Haag, Rainer et al., "Electrical Breakdown of Aliphatic and Aromatic Self-Assembled Monolayers Used as Nanometer-Thick Organic Dielectrics," J. Am. Chem. Soc., 1999, pp. 7895-7906.
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	Hofmann, F. et al., "Surrounding Gate Select Transistor for 4F ² Stacked Gbit DRAM," Infineon Technologies Corporate Research, Munich, Germany.

EXAMINER:

/Kevin Parendo/

DATE CONSIDERED:

10/07/2008

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

ALL REFERENCES CONSIDERED EXCEPT WHERE LINED THROUGH. /K.P./